## Accepted Manuscript

Real-time stress evolution in a high temperature superconducting thin film caused by a pulse magnetic field



Cong Liu, Xingyi Zhang, Miao Liu, You-He Zhou

PII:	S0040-6090(17)30599-0
DOI:	doi: 10.1016/j.tsf.2017.08.019
Reference:	TSF 36161
To appear in:	Thin Solid Films
Received date:	21 September 2016
Revised date:	9 August 2017
Accepted date:	11 August 2017

Please cite this article as: Cong Liu, Xingyi Zhang, Miao Liu, You-He Zhou, Realtime stress evolution in a high temperature superconducting thin film caused by a pulse magnetic field, *Thin Solid Films* (2017), doi: 10.1016/j.tsf.2017.08.019

This is a PDF file of an unedited manuscript that has been accepted for publication. As a service to our customers we are providing this early version of the manuscript. The manuscript will undergo copyediting, typesetting, and review of the resulting proof before it is published in its final form. Please note that during the production process errors may be discovered which could affect the content, and all legal disclaimers that apply to the journal pertain.

## ACCEPTED MANUSCRIPT

## Real-time stress evolution in a high temperature superconducting thin film caused by a pulse magnetic field

Cong Liu,<sup>1, 2</sup> Xingyi Zhang,<sup>1, 2, \*</sup> Miao Liu and You-He Zhou<sup>1, 2</sup>

<sup>1</sup>Key Laboratory of Mechanics on Disaster and Environment in Western China attached to the Ministry of Education of China,

Lanzhou University, Lanzhou,

Gansu 730000, PR China

<sup>2</sup>Department of Mechanics and Engineering Sciences, College of Civil Engineering and Mechanics, Lanzhou University,

Lanzhou, Gansu 730000, PR China

<sup>\*</sup> Corresponding author: <u>zhangxingyi@lzu.edu.cn</u> (X. Y. Zhang), <u>Tel:+86-931-8914560</u>, Fax:+86-931-8914561

Download English Version:

## https://daneshyari.com/en/article/5465811

Download Persian Version:

https://daneshyari.com/article/5465811

Daneshyari.com